

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10526427	TAKAGAWA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Hevey, John A	4116

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
252	62.56-62.59, 62.62-62.63	10/11/2007	jah

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST see search history	10/11/2007	jah
PALM inventor search	10/11/2007	jah

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>